

**Form 1449 (Modified)****Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

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Applicants:

MATENA, et al.

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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class
N1	A	US 5 748 882 A	May 05, 1998	HUANG YENNUN	—	—
N1	B	US 5 673 386 A	Sept. 30, 1997	BATRA JATINDER PAL SINGH	—	—
N1	C	US 5 778 369 A	July 07, 1998	WILSON GREGORY ALAN et al.	—	—
	D					
	E					

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	F							

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
N1	G	KLEMM, R. et al: "ENHANCING JAVA SERVER AVAILABILITY WITH JAS" SOFTWARE PRACTICE & EXPERIENCE, JOHN WILEY & SONS LTD. CHICHESTER, GB, vol. 31, no. 7, 16 March 2001 (2001-03-16), pages 697-716, XP001060148 ISSN: 0038-0644 abstract; figure 3, page 698, paragraph 4 – page 700, paragraph 4 – page 701, paragraph 2 – page 702, paragraph 5 – page 705, paragraph 4 – page 709, paragraph 4
N1	H	MAFFEIS SILVANO: "Piranha: A COBRA tool for high availability" COMPUTER, IEEE COMPUTER SOCIETY, LONG BEACH, CA, US, US, vol. 30, no. 4, April 1997 (1997-04), pages 59-66, XP002162926 ISSN: 0018-9162 page 60 –page 62
N1	I	"METHOD TO CORRELATE ERROR REPORT TO SOURCE CODE" IBM TECHNICAL DISCLOSURE BULLETIN, IBM CORP. NEW YORK, US, vol. 29, no. 12, 1 May 1987 (1987-05-01), page 5315 XP000714424 ISSN: 0018-8689 the whole document
N1	J	RICHARD G G III et al.: "On patterns for practical fault tolerant software in Java" RELIABLE DISTRIBUTED SYSTEMS, 1998. PROCEEDINGS. SEVENTEENTH IEEE SYMPOSIUM ON WEST LAFAYETTE, IN, USA 20-23 OCT. 1998, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 20 October 1998 (1998-10-20), pages 144-150, XP010319078 ISBN: 0-8186-9218-9 abstract paragraph '0003.'
Examiner <i>Nadeem Z. Jhal</i>		Date Considered 6-9-04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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